

Amendments to Specification

Please amend the Specification as follows:

On page 20, in the first paragraph, delete that paragraph and insert the following:

-- A block diagram of another embodiment of the present invention is shown in Figure 5. In this embodiment, the test apparatus 300 includes a plurality of testers 336/308/370, each being coupled to a single handler 304 via a corresponding test head 344/310/374 [34/310/374], respectively. First tester 336 may comprise a low cost tester and the test apparatus 300 may not include an environmental test chamber for IC's to be tested by the first tester 336 within the handler 304, for example. Second tester 308 and third tester 370 may comprise high cost testers, and the apparatus 300 may include an environmental chamber 361 for IC's under test by the second tester 308, and/or an environmental chamber 376 for IC's under test by the third tester 370. The environmental chambers 361/376 may be adapted to subject IC's to different environmental tests, e.g. the environment parameters of environmental chamber 361 may be different than the environmental parameters of environmental chamber 376. A plurality of other testers, not shown, may be included in the test apparatus 300. Sets of IC's may be tested with test procedures from the first, second and third testers 336/308/370 in parallel, or simultaneously, in accordance with this embodiment of the present invention.--